



# STL16N65M5

N-channel 650 V, 0.270  $\Omega$ , 12 A PowerFLAT™ 8x8 HV MDmesh™ V Power MOSFET

## Features

Order code	V <sub>DSS</sub> @ T <sub>Jmax</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
STL16N65M5	710 V	< 0.299 $\Omega$	12 A <sup>(1)</sup>

1. The value is rated according to R<sub>thj-case</sub>

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

## Applications

- Switching applications

## Description

This device is an N-channel MDmesh™ V Power MOSFET based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH™ horizontal layout structure. The resulting product has extremely low on-resistance, which is unmatched among silicon-based Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

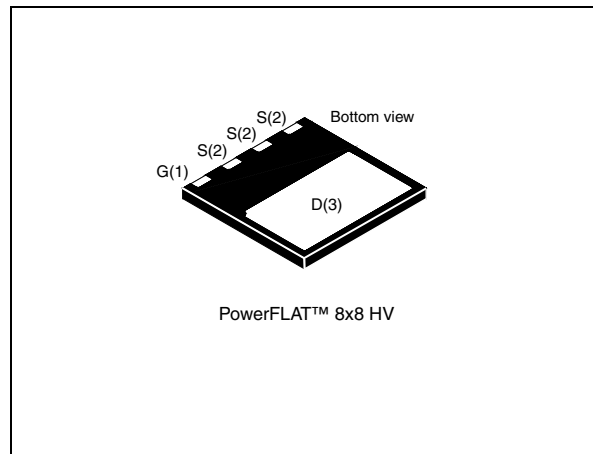


Figure 1. Internal schematic diagram

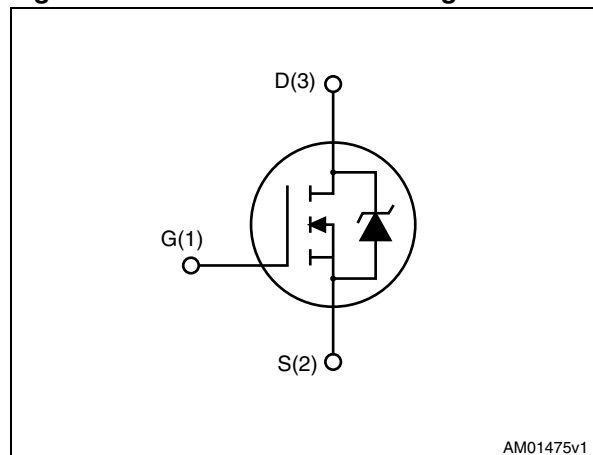


Table 1. Device summary

Order code	Marking	Package	Packaging
STL16N65M5	16N65M5	PowerFLAT™ 8x8 HV	Tape and reel

# Contents

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# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage ( $V_{GS} = 0$ )	650	V
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D^{(1)}$	Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$	12	A
$I_D^{(1)}$	Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$	7.4	A
$I_{DM}^{(1),(2)}$	Drain current (pulsed)	48	A
$I_D^{(3)}$	Drain current (continuous) at $T_{amb} = 25\text{ }^\circ\text{C}$	2	A
$I_D^{(3)}$	Drain current (continuous) at $T_{amb} = 100\text{ }^\circ\text{C}$	1.3	A
$I_{DM}^{(2),(3)}$	Drain current (pulsed)	8	A
$P_{TOT}^{(3)}$	Total dissipation at $T_{amb} = 25\text{ }^\circ\text{C}$	3	W
$P_{TOT}^{(1)}$	Total dissipation at $T_C = 25\text{ }^\circ\text{C}$	90	W
$I_{AR}$	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_j$ max)	4	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25\text{ }^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ )	200	mJ
$dv/dt^{(4)}$	Peak diode recovery voltage slope	15	V/ns
$T_{stg}$	Storage temperature	- 55 to 150	$^\circ\text{C}$
$T_j$	Max. operating junction temperature	150	$^\circ\text{C}$

1. The value is rated according to  $R_{thj-case}$
2. Pulse width limited by safe operating area
3. When mounted on FR-4 board of  $1\text{ inch}^2$ , 2oz Cu
4.  $I_{SD} \leq 12\text{ A}$ ,  $di/dt \leq 400\text{ A}/\mu\text{s}$ ,  $V_{Peak} < V_{(BR)DSS}$ ,  $V_{DD} = 400\text{ V}$

**Table 3. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	1.38	$^\circ\text{C}/\text{W}$
$R_{thj-amb}^{(1)}$	Thermal resistance junction-amb max	45	$^\circ\text{C}/\text{W}$

1. When mounted on  $1\text{ inch}^2$  FR-4 board, 2 oz Cu

## 2 Electrical characteristics

( $T_C = 25\text{ °C}$  unless otherwise specified)

**Table 4. On /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage ( $V_{GS} = 0$ )	$I_D = 1\text{ mA}$	650			V
$I_{DSS}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = 650\text{ V}$ $V_{DS} = 650\text{ V}, T_C = 125\text{ °C}$			1 100	$\mu\text{A}$ $\mu\text{A}$
$I_{GSS}$	Gate-body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 25\text{ V}$			100	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	3	4	5	V
$R_{DS(on)}$	Static drain-source on resistance	$V_{GS} = 10\text{ V}, I_D = 6\text{ A}$		0.270	0.299	$\Omega$

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100\text{ V}, f = 1\text{ MHz},$ $V_{GS} = 0$	-	1250	-	pF
$C_{oss}$	Output capacitance			30		pF
$C_{rss}$	Reverse transfer capacitance			3		pF
$C_{o(tr)}^{(1)}$	Equivalent capacitance time related	$V_{DS} = 0\text{ to }520\text{ V}, V_{GS} = 0$	-	100	-	pF
$C_{o(er)}^{(2)}$	Equivalent capacitance energy related			30		pF
$R_G$	Intrinsic gate resistance	$f = 1\text{ MHz open drain}$	-	2	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 520\text{ V}, I_D = 6\text{ A},$ $V_{GS} = 10\text{ V}$ (see <a href="#">Figure 16</a> )	-	31	-	nC
$Q_{gs}$	Gate-source charge			8		nC
$Q_{gd}$	Gate-drain charge			12		nC

- $C_{oss\text{ eq.}}$  time related is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$
- $C_{oss\text{ eq.}}$  energy related is defined as a constant equivalent capacitance giving the same stored energy as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

**Table 6. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
$t_d$ (v)	Voltage delay time	$V_{DD} = 400$ V, $I_D = 8$ A,		25		ns
$t_r$ (v)	Voltage rise time	$R_G = 4.7$ $\Omega$ , $V_{GS} = 10$ V		7		ns
$t_f$ (i)	Current fall time	(see <a href="#">Figure 17</a> ),	-	6	-	ns
$t_c$ (off)	Crossing time	(see <a href="#">Figure 20</a> )		8		ns

**Table 7. Source drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current				12	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		48	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 12$ A, $V_{GS} = 0$	-		1.5	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 12$ A, $di/dt = 100$ A/ $\mu$ s		300		ns
$Q_{rr}$	Reverse recovery charge	$V_{DD} = 100$ V (see <a href="#">Figure 17</a> )	-	3.5		$\mu$ C
$I_{RRM}$	Reverse recovery current			23		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 12$ A, $di/dt = 100$ A/ $\mu$ s		350		ns
$Q_{rr}$	Reverse recovery charge	$V_{DD} = 100$ V, $T_j = 150$ °C	-	4		$\mu$ C
$I_{RRM}$	Reverse recovery current	(see <a href="#">Figure 17</a> )		24		A

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300  $\mu$ s, duty cycle 1.5%

## 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

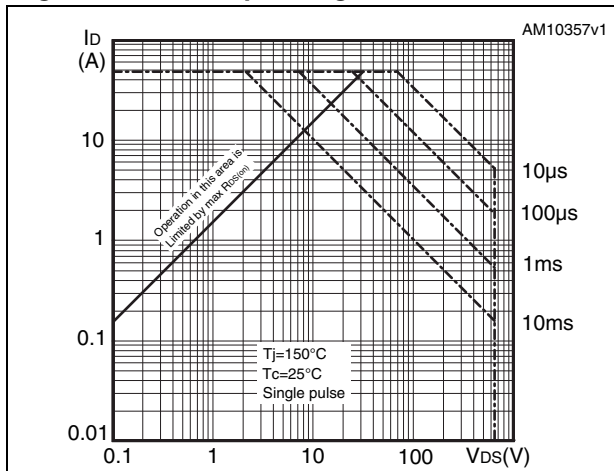


Figure 3. Thermal impedance

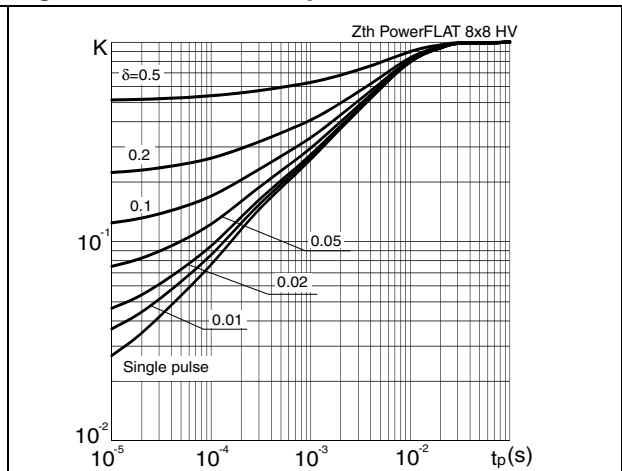


Figure 4. Output characteristics

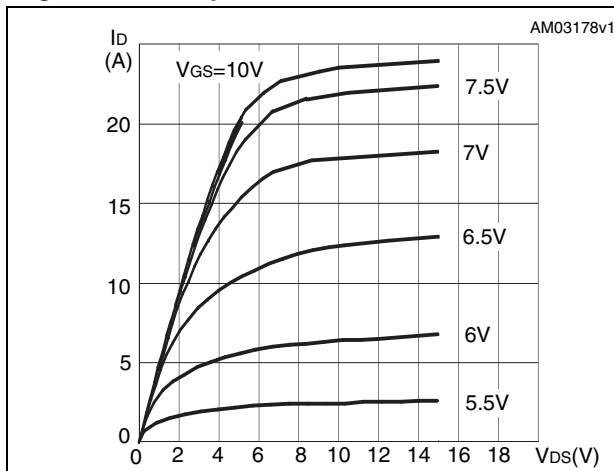


Figure 5. Transfer characteristics

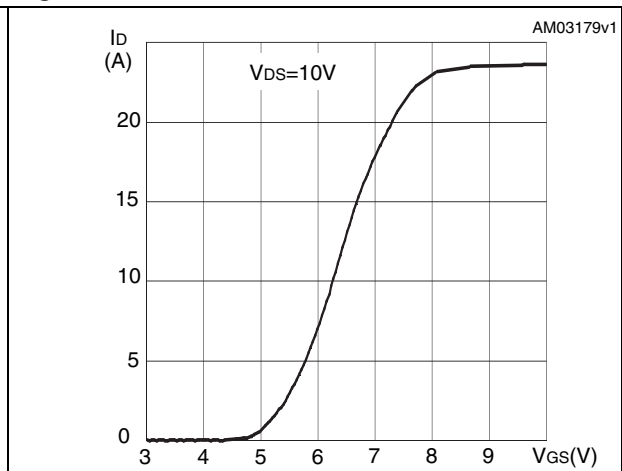


Figure 6. Normalized  $B_{V_{DS}}$  vs temperature

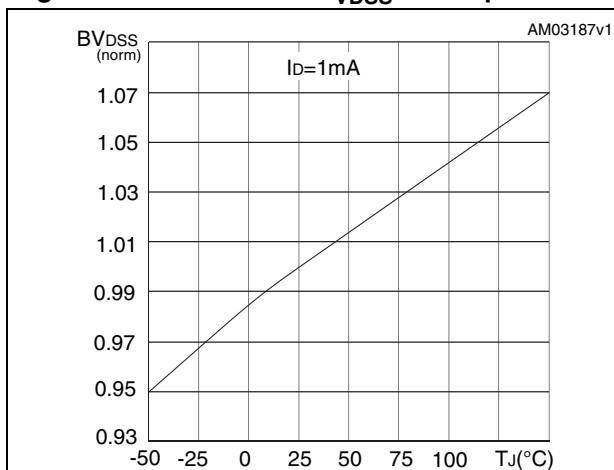


Figure 7. Static drain-source on resistance

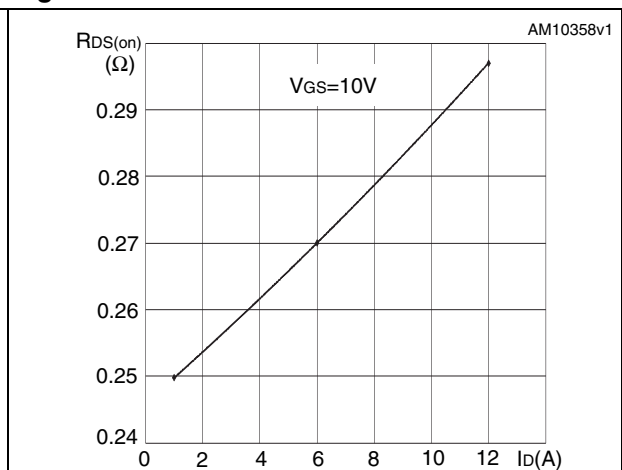


Figure 8. Output capacitance stored energy

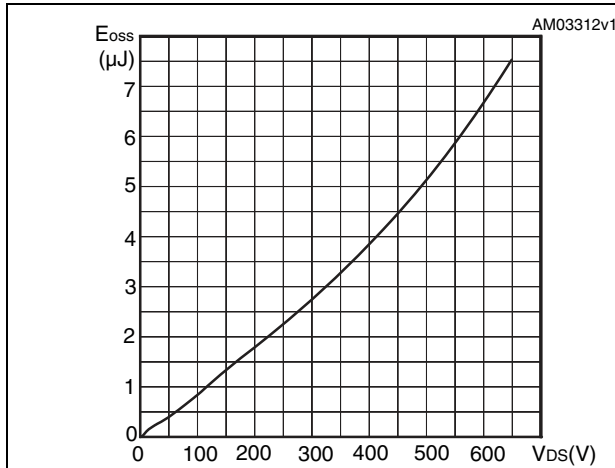


Figure 9. Capacitance variations

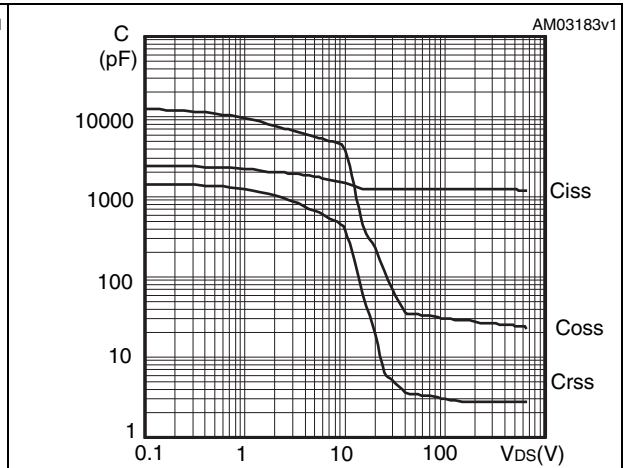


Figure 10. Gate charge vs gate-source voltage

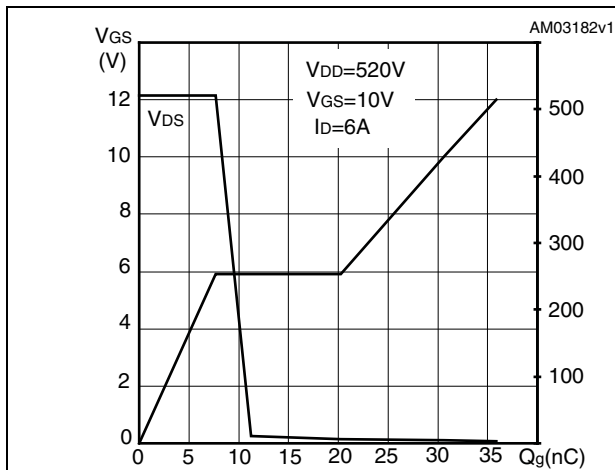


Figure 11. Normalized on resistance vs temperature

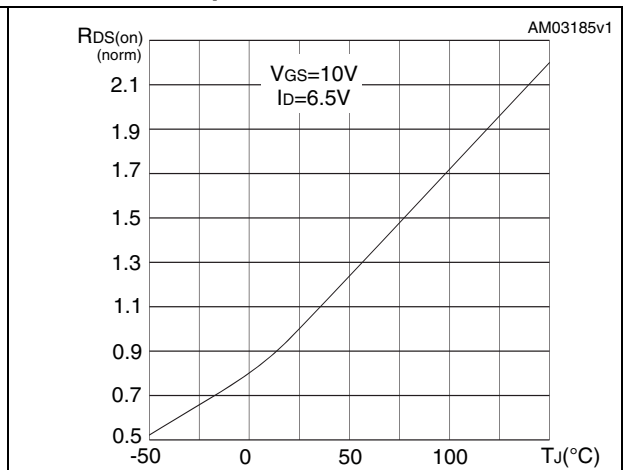


Figure 12. Normalized gate threshold voltage vs temperature

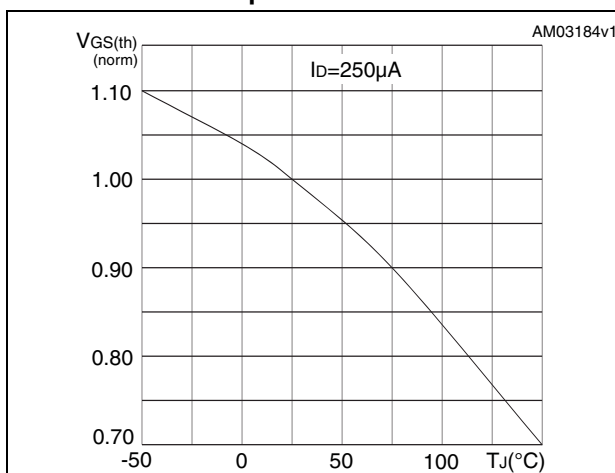


Figure 13. Source-drain diode forward characteristics

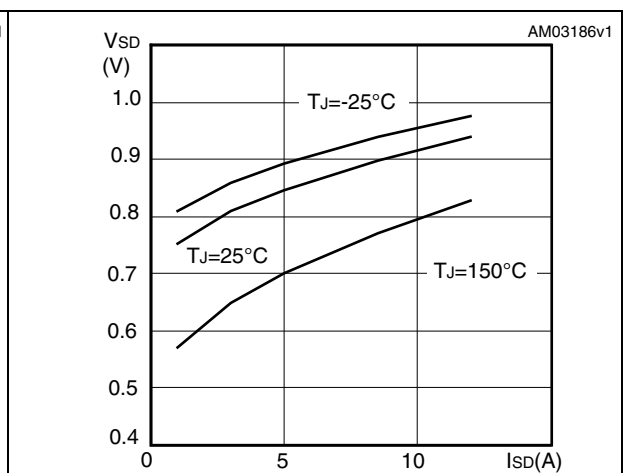
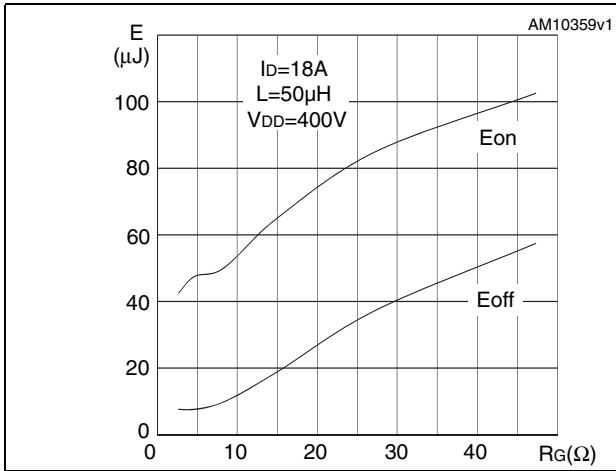


Figure 14. Switching losses vs gate resistance (1)

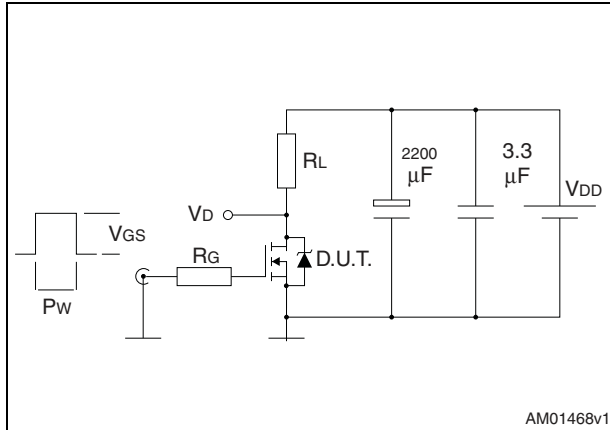


1. Eon including reverse recovery of a SiC diode

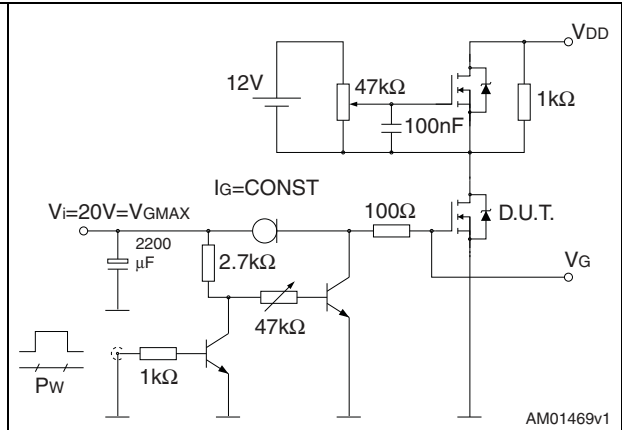


### 3 Test circuits

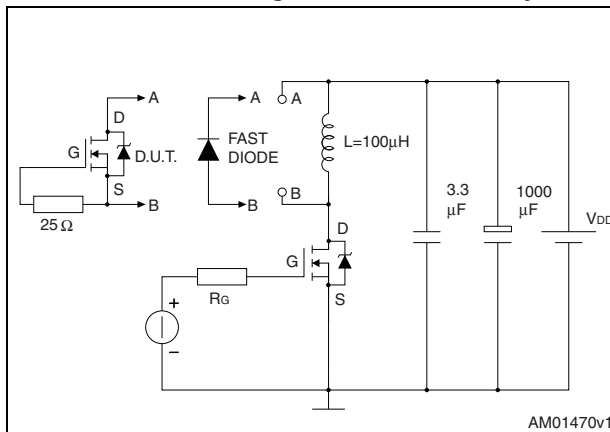
**Figure 15. Switching times test circuit for resistive load**



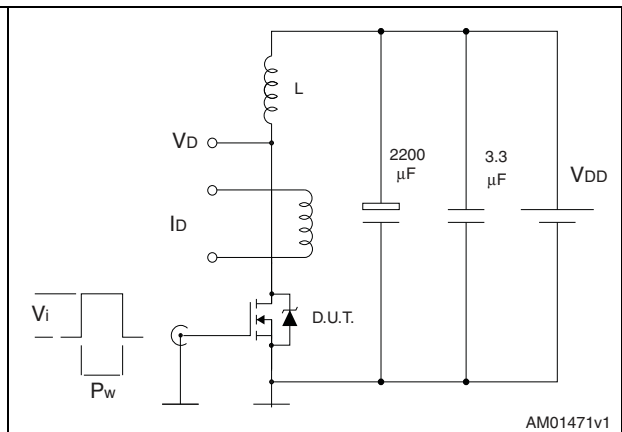
**Figure 16. Gate charge test circuit**



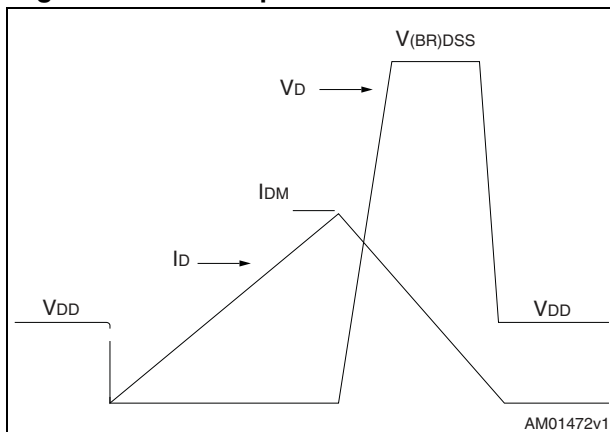
**Figure 17. Test circuit for inductive load switching and diode recovery times**



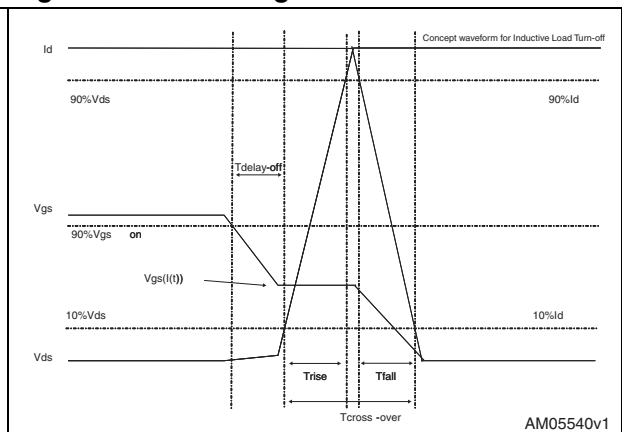
**Figure 18. Unclamped inductive load test circuit**



**Figure 19. Unclamped inductive waveform**



**Figure 20. Switching time waveform**



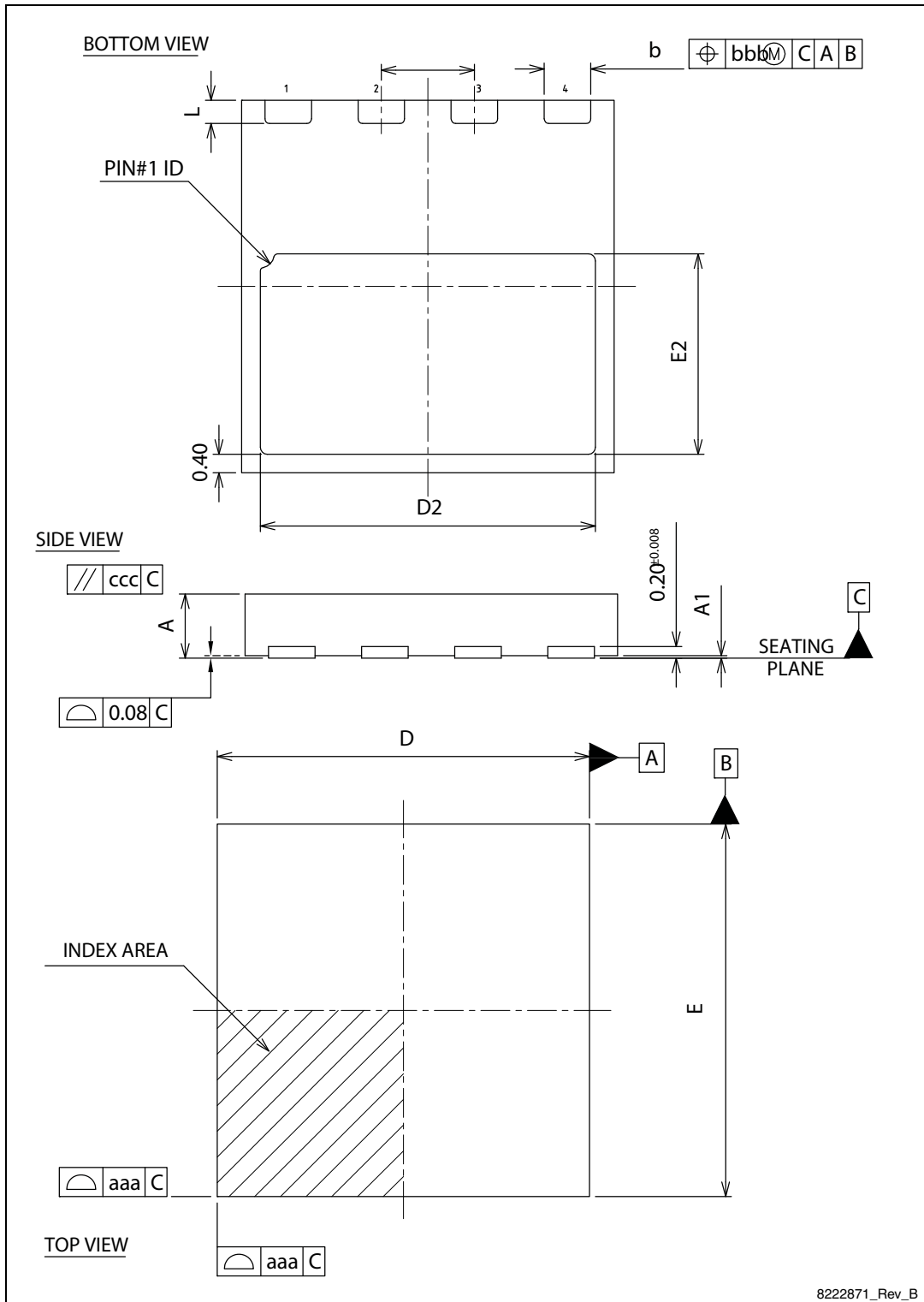
## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

Table 8. PowerFLAT™ 8x8 HV mechanical data

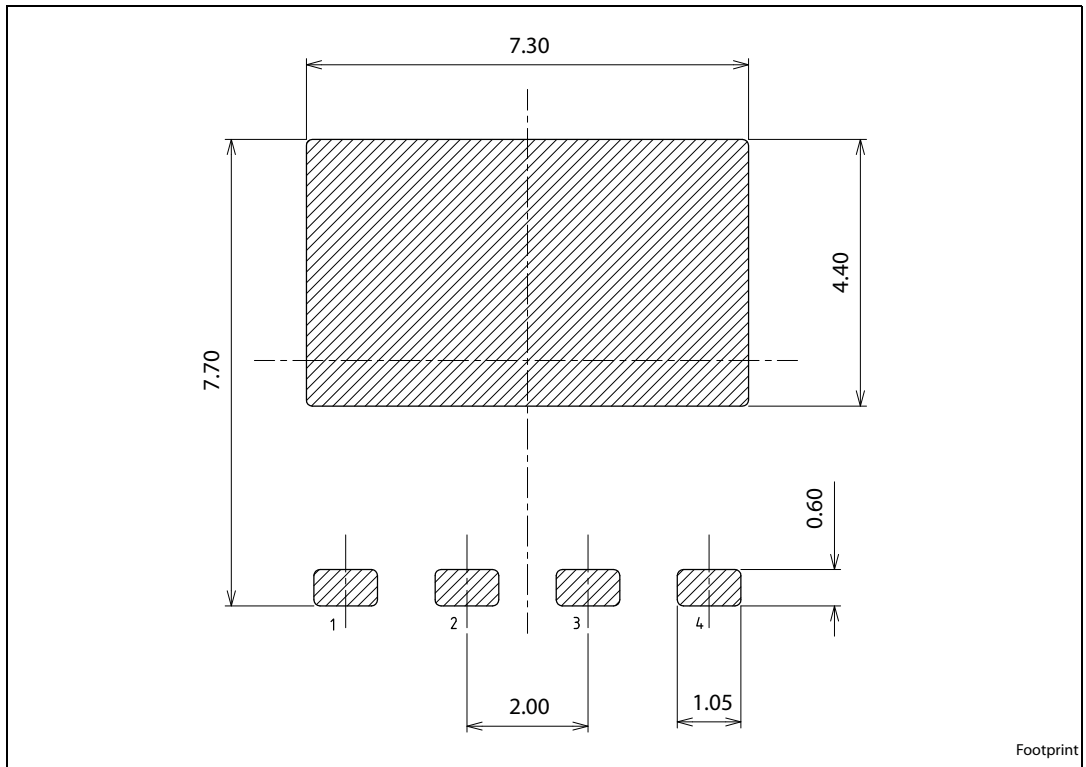
Dim.	mm		
	Min.	Typ.	Max.
A	0.80	0.90	1.00
A1	0.00	0.02	0.05
b	0.95	1.00	1.05
D		8.00	
E		8.00	
D2	7.05	7.20	7.30
E2	4.15	4.30	4.40
e		2.00	
L	0.40	0.50	0.60
aaa		0.10	
bbb		0.10	
ccc		0.10	

Figure 21. PowerFLAT™ 8x8 HV drawing mechanical data



8222871\_Rev\_B

Figure 22. PowerFLAT™ 8x8 HV recommended footprint



## 5 Revision history

**Table 9. Document revision history**

Date	Revision	Changes
30-Apr-2010	1	First release
08-Jun-2010	2	$V_{GS}$ value has been changed in <a href="#">Table 4</a>
10-Feb-2011	3	Modified $R_{DS(on)}$ value
28-Jul-2011	4	Document status promoted from preliminary data to datasheet Added <a href="#">Section 2.1: Electrical characteristics (curves)</a> Minor text changes
03-Nov-2011	5	<a href="#">Section 4: Package mechanical data</a> has been modified.

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